

Notice of References Cited	Application/Control No. 10/614,429	Applicant(s)/Patent Under Reexamination SCHILZ ET AL.	
	Examiner Richard Bueker	Art Unit 1763	Page 1 of 1

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	C	US-5,147,823	09-1992	Ishibashi et al.	438/694
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	M	US-			

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NON-PATENT DOCUMENTS

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	U	Utke, Microelectronic Engineering 53 (2000) 261-264
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.